- to see how well any of these smoothing methods work, need a notion of 'long-run' performance
- e.g. if we assume $Y = f(X) + \epsilon$ and our method gives $\hat{f}(\cdot)$ based on $(x_1, y_n), \ldots, (x_N, y_N)$:
 - Does $\widehat{f}(x_0) \to f(x_0)$, $N \to \infty$? all x_0 ?
 - Is $\sqrt{n}{\hat{f}(x_0) f(x_0)}$ asymptotically normal? variance?
 - Is $Ef(x_0) = f(x_0)$? (unbiased?)
- assume we have a a loss function, i.e. a measure of distance from Y to f(X)

$$L(Y,\widehat{f}(X)) = (Y - \widehat{f}(X))^2$$

Test error, generalization error:

$$\operatorname{Err} = E[L\{Y, \widehat{f}(X)\}]$$

over the distribution of Y, X, and \hat{f} .



• Test error: Err =
$$EL{Y, \hat{f}(X)}$$
:
 $\hat{f}(X) = \hat{f}(X; x_1, y_1, \dots, x_N, y_N) = \hat{f}(X, t_N)$, say

• distribution of f(X) depends on distribution of X and t_N

• Err =
$$E_{X,Y,t_N}L\{Y,\widehat{f}(X)\}$$

- ► **Training error**: average loss in training sample $\overline{\text{err}} = \frac{1}{N} \sum_{i=1}^{N} L\{y_i, \hat{f}(x_i)\}$
- As f(·) becomes more complex, training error will decrease (eventually to 0) but test error will increase, because f(·) fits observed data exactly



- Test error at a fixed x_0 : Err $(x_0) = E[L\{Y, \hat{f}(x_0)\}]$
- depends on distribution of Y and $\hat{f}(x_0) = \hat{f}(x_0; t_N)$
- under squared error loss

$$\operatorname{Err}(x_0) = \sigma^2 + \operatorname{Bias}^2 \widehat{f}(x_0) + \operatorname{var} \widehat{f}(x_0)$$

- Example: k-nearest neighbour estimate *f*(x₀) = ¹/_k ∑^N_{i=1} y_i1{x_i ∈ N_k(x₀)}
 Ef(x₀) = ¹/_k ∑ *E*[y_i1{x_i ∈ N_k(x₀)}]

 assume x_i are fixed = ¹/_k ∑^N_{i=1} *E*(y_i)1{x_i ∈ N_k(x₀)} = ¹/_k ∑^k_{ℓ=1} f(x_(ℓ))

 var *f*(x₀) = σ²/k
- **•** see Eq. (7.9) ; note have assumed training x_i are fixed

- Example: linear regression: $\hat{f}(x_0) = x_0^T \hat{\beta}$
- ► $\operatorname{var} \hat{f}(x_0) = \operatorname{var}(x_0^T \hat{\beta}) = \operatorname{var} x_0^T \{ (X^T X)^{-1} X^T y \}$ where X and y refer to training data
- ► = var($a^T y$), say, = $\sigma^2 a^T a = \sigma^2 ||a||^2 = \sigma^2 ||x_0(X^T X)^{-1} X^T x_0||^2 = \sigma^2 ||h(x_0)||^2$
- note have assumed training x_i are fixed
- $\operatorname{Err}(x_0) = \sigma^2 + \operatorname{Bias}^2 \widehat{f}(x_0) + \sigma^2 ||h(x_0)||^2$
- a rough guide to $\operatorname{Err}(x_0)$ is $\frac{1}{N}\sum \operatorname{Err}(x_i) = \sigma^2 + \frac{1}{N}\sum \{f(x_i) - E\widehat{f}(x_i)\}^2 + \sigma^2 p/N$
- shows that Err increases as p increases
- ► similarly for ridge regression $\operatorname{Err}(x_0) = \sigma^2 + \operatorname{Bias}^2 \widehat{f}^{ridge}(x_0) + \sigma^2 ||h^{ridge}(x_0)||^2$
- $h^{ridge}(x_0) = x_0^T (X^T X + \lambda I)^{-1} x_0$

§7.3 and 7.4 discuss instead the estimation of "in-sample error", not quite the same as test error

• Err_{in} =
$$\frac{1}{N} \sum_{i=1}^{N} E_y E_{Y^{new}}[L\{Y_i^{new}, \hat{f}(x_i)\}]$$

- test values Y^{new}_i observed at training points x_i
- Claim $\operatorname{Err}_{in} = E_y \overline{err} + (2/N) \sum_{i=1}^N \operatorname{cov}(\hat{y}_i, y_i)$ (7.18)
- For squared error loss, a vague sketch

$$\overline{err} = \frac{1}{N} \sum (y_i - \hat{y}_i)^2$$

= $\frac{1}{N} \sum (y_i - f(x_i) + f(x_i) - \hat{y}_i)^2$
= $\frac{1}{N} \sum (y_i - f(x_i))^2 + \frac{1}{N} \sum \{\hat{y}_i - f(x_i)\}^2$
 $-\frac{2}{N} \sum \{y_i - f(x_i)\} \{\hat{y}_i - f(x_i)\}$

- ► If $\hat{y} = Sy$, where *S* has *d* degrees of freedom, then $\sum \text{cov}(\hat{y}_i, y_i) = d\sigma^2$
- $\operatorname{Err}_{in} = E_y \overline{err} + \frac{2}{N} d\sigma^2$
- Err_{in} relevant for model selection, and easier to analyse than Err
- Estimating Err_{in} : for example $\overline{err} + \frac{2}{N} d\sigma^2$: this is C_p
- AIC replaces $\frac{1}{N} \sum (y_i \hat{y}_i)^2$ with $-\frac{2}{N} \log(\hat{\theta}; y)$
- see Figure 7.4

- Generalization/test error $\operatorname{Err} = E_{X,Y,\hat{f}}[L\{Y,\hat{f}(X)\}]$
- Cross-validation attempts to estimate this directly

•
$$CV = \frac{1}{N} \sum L\{y_i, \widehat{f}^{\kappa(i)}(x_i)\}$$
 (7.42)

- κ(i) indexes which of K partitions observation i is in (K-fold CV)
- If \hat{f} depends on a tuning parameter, α , then we compute
- $CV(\alpha) = \frac{1}{N} \sum L\{y_i, \hat{f}^{\kappa(i)}(x_i, \alpha)\}$ for a variety of choices
- K = 1 has low bias but high variance; large K the opposite; K = 5 or 10 recommended
- generalized CV is an approximation to CV with K = 1 used in linear fitting methods with squared error loss
- (GCV is used by the Im.ridge program)